Modeling, Design and Optimization of On-Chip Inductors and Transformers

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THE GOAL



Simple, Accurate Expressions for Inductance

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OUTLINE

- Background
- Current Sheet Approach
- Accurate Inductance Expressions
- Optimization of Inductor Circuits
- Transformer Modeling
- Contributions

ON-CHIP INDUCTORS AND TRANSFORMERS

- Essential for radio frequency integrated circuits (RFICs)
- Narrowband circuits
 - **{** Low noise amplifiers, oscillators, filters, matching networks, baluns
- Broadband circuits
 - { Shunt-peaking to enhance bandwidth

ON-CHIP INDUCTOR OPTIONS

Attribute	Bond wire	Planar Spiral
Inductance	$0.5 - 4 \mathrm{nH}$	0.2 - 100 nH
Q	30 - 60	< 10
Parasitics	$C_{\rm Bondpad}$	$R_{ m s}$, $C_{ m ox}$, $C_{ m si}$, $R_{ m si}$
Fluctuations	Large	Small

LATERAL PARAMETERS



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LATERAL PARAMETERS

- 1. Shape: square, hexagonal, octagonal, ...
- 2. Number of turns, n
- 3. Conductor width, \boldsymbol{w}
- 4. Conductor spacing, s

5.
$$d_{\text{out}}$$
, d_{in} , $d_{\text{avg}} = 0.5(d_{\text{out}} + d_{\text{in}})$, or $\rho = \frac{d_{\text{out}} - d_{\text{in}}}{d_{\text{out}} + d_{\text{in}}}$

VERTICAL PARAMETERS



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MODELING APPROACHES

- 3-D field solvers
- Segmented models
- Lumped, Scalable models

3-D FIELD SOLVERS

- General Purpose Tools
 - { Solve Maxwell's equations numerically
 - { Accurate, but slow and memory intensive
 - { Examples: *Maxwell*, *MagNet*
- Custom Tools for Spiral Inductors and Transformers
 - **{** Electrostatic and Magnetostatic approximations
 - { Good for verification, but inconvenient for circuit design and synthesis
 - { Examples: ASITIC, SPIRAL

SEGMENTED MODELS



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LUMPED, SCALABLE MODELS



- Simple expressions for $R_{
 m s}$, $C_{
 m ox}$ and $C_{
 m s}$
- **NEED** simple, accurate expression for inductance!
- Limitations:
 - { Magnetic coupling to substrate **NOT** modeled
 - { Lumped approximation not valid beyond self-resonant frequency

Find self inductance of, and mutual inductance between every segment of spiral:

$$\mathcal{M}_{gen,i,j} = \begin{bmatrix} L_1 & M_{1,2} & \dots & M_{1,(n-1)} & M_{1,n} \\ M_{1,2} & L_2 & \dots & M_{2,(n-1)} & M_{2,n} \\ \dots & \dots & \dots & \dots & \dots \\ M_{1,(n-1)} & M_{2,(n-1)} & \dots & L_{(n-1)} & M_{n,(n-1)} \\ M_{1,n} & M_{2,n} & \dots & M_{n,(n-1)} & L_n \end{bmatrix}$$
$$L_{\mathrm{T}} = \sum_{i=1}^n L_i + \sum_{i=1}^n \sum_{j=1, j \neq i}^n M_{i,j}$$

PREVIOUSLY REPORTED EXPRESSIONS

Voorman :
$$L_{voo} = 10^{-3} n^2 d_{avg}$$

Dill : $L_{dil} = 8.5 \cdot 10^{-4} n^{5/3} d_{avg}$
Bryan : $L_{bry} = 2.41 \cdot 10^{-3} n^{5/3} d_{avg} \log(4/\rho)$
Ronkanien : $L_{ron} = 1.5 \mu_0 n^2 e^{-3.7(n-1)(w+s)/d_{out}}$
Crols : $L_{cro} = 1.3 \cdot 10^{-4} (d_{out}^3/w^2) \eta_a^{5/3} \eta_w^{1/4}$

- Empirical expressions
- Significant mean offset errors
- Even when corrected, errors > 15 20%

DERIVATION OF ACCURATE EXPRESSIONS

• Use equivalent current sheet to simplify problem:



• Use GMD, AMD and AMSD to derive simple expression

GEOMETRIC MEAN DISTANCE (GMD)

• For distances d_1 and d_2 :

$$\text{GMD} = \sqrt{d_1 d_2}$$

$$\ln(\text{GMD}) = \frac{1}{2} \left[\ln(d_1) + \ln(d_2) \right]$$

• For n distances:

$$\ln(\text{GMD}) = \frac{1}{n} \left[\ln(d_1) + \ln(d_2) \cdots + \ln(d_n) \right]$$

GMD IN INDUCTANCE CALCULATIONS

Need to evaluate of GMD of conductor cross-section(s):
 { Self: GMD of conductor cross-section from itself

{ Mutual: GMD between two conductor cross-sections

- Use continuous variable definition of GMD
 { Need integrals rather than sums
- GMD introduced in to inductance calculations by J. C. Maxwell

GMD IN INDUCTANCE CALCULATIONS

• For cross sections in one dimension (current sheets):

$$l_1 l_2 \ln(\text{GMD}) = \iint \ln(r) \, dx \, dx'$$

{ l_1 and l_2 are the lengths of the cross-sections { dx and dx' are the elements of the cross-sections { r is the distance between the elements

GMD BETWEEN TWO LINES



 Basis for mutual inductance calculations in Greenhouse method

GMD, AMD AND AMSD OF A LINE



PARALLEL LINES OF EQUAL LENGTH



INDUCTANCE OF CURRENT SHEET



$$M = \frac{\mu l}{2\pi} \left[\ln(2l) - \ln(R) - 1 + \frac{R}{l} - \frac{R^2}{4l^2} \right]$$
$$L_{\rm s} = \frac{\mu l}{2\pi} \left[\ln(2l) - \ln(\text{GMD}) - 1 + \frac{\text{AMD}}{l} - \frac{\text{AMSD}^2}{4l^2} \right]$$

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INDUCTANCE OF RECTANGULAR CURRENT SHEET



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EQUIVALENT RECTANGULAR CURRENT SHEET



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APPROXIMATING A SQUARE SPIRAL



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One Side of a Square Spiral: $L_{\rm s}$



Opposite Sides of a Square Spiral: $M_{\rm opp}$



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CURRENT SHEET EXPRESSION FOR A SQUARE SPIRAL



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CONCENTRIC CIRCULAR CONDUCTORS



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CURRENT SHEET EXPRESSIONS

$$L_{\rm cursh} = \frac{\mu n^2 d_{\rm avg} c_1}{2} \left[\ln(c_2/\rho) + c_3 \rho + c_4 \rho^2 \right]$$

Layout	c_1	c_2	c_3	c_4
Square	1.27	2.07	0.18	0.13
Hexagonal	1.09	2.23	0.00	0.17
Octagonal	1.07	2.29	0.00	0.19
Circle	1.00	2.46	0.00	0.20

OTHER INDUCTANCE EXPRESSIONS

• Monomial Expression :

$$L_{\rm mon} = \beta d_{\rm out}^{\alpha_1} w^{\alpha_2} d_{\rm avg}^{\alpha_3} n^{\alpha_4} s^{\alpha_5}$$

• Modified Wheeler Expression :

$$L_{\rm mw} = K_1 \mu_0 \frac{n^2 d_{\rm avg}}{1 + K_2 \rho}$$

COMPARISON TO FIELD SOLVERS: PREVIOUS WORK



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COMPARISON TO FIELD SOLVERS: NEW WORK



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EXPERIMENTAL SET-UP



COMPARISON TO EXPERIMENTS: PREVIOUS WORK



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COMPARISON TO EXPERIMENTS: NEW WORK



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PARAMETERS OF INTEREST

• Inductor quality factor ($Q_{\rm L}$)

$$Q_L = 2\pi \frac{\left[\text{peak magnetic energy} - \text{peak electric energy}\right]}{\text{energy loss in one oscillation cycle}}$$

• Tank quality factor (Q_{tank})

 $Q_{\rm tank} = 2\pi \frac{\rm peak\ magnetic\ energy}{\rm energy\ loss\ in\ one\ oscillation\ cycle}$

• Self-resonance frequency ($\omega_{\rm res}$), frequency at which $Q_{\rm L}=0$

Example: Maximum Q_L @ 2GHz for L = 8nH



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EXAMPLE: SHUNT-PEAKED AMPLIFIER

Common Source Amplifier

Shunt-peaked Amplifier



- Bandwidth enhancement using zeros
- No additional power dissipation

ON-CHIP SHUNT PEAKING



- Work with inductor parasitics
- *R*_s is **not** an issue (now part of load resistance)
- Inductor Q is not relevant
- Minimize area and $C_{\rm L}$
- L determined by R , $C_{\rm load}$, $C_{\rm L}$ and $C_{\rm d}$

SHUNT-PEAKED TRANSIMPEDANCE AMPLIFIER



- Input current drive
- Cascode stage
- On-chip shunt-peaking

• Feedback

DESIGN METHODOLOGY

- 1. Design and optimize transimpedance stage without shunt peaking
- 2. Transistor current determines conductor width, \boldsymbol{w}
- 3. Lithography sets spacing, s
- 4. Choose n and AD to realize desired L while minimizing parasitic capacitance and area
- 5. Maximize transimpedance resistance, $R_{
 m f}$

TRANSFORMER



•
$$v_1 = L_1 \frac{\partial i_1}{\partial t} + M \frac{\partial i_2}{\partial t}$$

 $v_2 = L_2 \frac{\partial i_2}{\partial t} + M \frac{\partial i_1}{\partial t}$

• Mutual coupling coefficient, $k = \frac{M}{\sqrt{L_1 L_2}}$

•
$$|k| \leq 1$$

NON-IDEAL TRANSFORMER



- Series resistance.
- Port-to-port & port-to-substrate capacitances

TAPPED TRANSFORMER



- advantages: { High L_1 , L_2
 - { Top metal layer
 - { Low port-to-port capacitance
- disadvantages: { Asymmetric { Low $k (\approx 0.3 - 0.5)$

INTERLEAVED TRANSFORMER



- advantages:
 - { Medium k $(\approx 0.7 0.8)$
 - { Symmetric
 - { Top metal layer
- disadvantages:
 - { Medium port-to-port capacitance
 - { Low L_1 , L_2

STACKED TRANSFORMER

Top View



- advantages: { High $k (\approx 0.9)$
 - { High L_1 , L_2
 - { Area efficient
- disadvantages:
 - { Multiple metal layers
 - { High port-to-port &
 port-to-substrate
 capacitances

STACKED TRANSFORMER VARIATIONS



- Shift top and bottom spirals laterally or diagonally
- Trade-off lower k for reduced port-to-port capacitance

COMPARISON OF TRANSFORMER REALIZATIONS

Transformer	Area	Coupling	Self-	Self-resonant
type		coefficient, k	inductance	frequency
Tapped	High	Low	Mid	High
Interleaved	High	Mid	Low	High
Stacked	Low	High	High	Low

- Non-idealities result in trade-offs
- Optimal choice determined by circuit application
- Transformer models needed for comparison

TAPPED TRANSFORMER MODEL





- Evaluate $C_{\rm ov,o}$, $C_{\rm ox,o}$, $C_{\rm ox,i}$, $R_{\rm s,o}$ & $R_{\rm s,i}$ by extending previous work
- Use inductance expression for $L_{\rm s,o}$, $L_{\rm s,i}$
- $\bullet \ {\rm Calculate} \ M$

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MUTUAL INDUCTANCE CALCULATION

Single inductor.



Tapped transformer.



Interleaved transformer.



STACKED TRANSFORMER MODEL





- Evaluate $C_{\rm ov}$, $C_{\rm ox,t}$, $C_{\rm oxm}$, $C_{\rm ox,b}$, $R_{\rm s,t}$ & $R_{\rm s,b}$ by extending previous work
- \bullet Use inductance expression for $L_{\rm s,t}$, $L_{\rm s,b}$
- $\bullet \ {\rm Calculate} \ M$
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CURRENT SHEET APPROACH FOR k



- \bullet Reduce complexity by $4n^2$
- Use symmetry
- Derive simple expression using electromagnetic theory

<u>k for Stacked Transformers</u>



• Metal and oxide thicknesses have only 2nd order effects on k

EXPERIMENTAL SET-UP



EXPERIMENTAL VERIFICATION: TAPPED

- $OD_o = 290 \mu m$, $n_o = 2.5$
- $OD_i = 190 \mu m$, $n_i = 4.25$

1.0

0.5

0.0

-0.5

-1.0 ∟ 0.8

 \mathbf{S}_{21}

• $w = 13 \mu m, s = 7 \mu m$

 \blacktriangle real(S₂₁) meas

• $imag(S_{21})$ meas

1.6

Frequency (GHz)

2.0

2.4

- real(S_{21}) calc - imag(S_{21}) calc

1.2





EXPERIMENTAL VERIFICATION: STACKED 1

- Stacked transformer with top spiral overlapping bottom one
- OD = $180\mu \text{m}$, n = 11.75, $w = 3.2\mu \text{m}$, $s = 2.1\mu \text{m}$
- $x_{
 m s}=0\mu{
 m m}, y_{
 m s}=0\mu{
 m m},$ $d_{
 m s}=0\mu{
 m m}$





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FUTURE WORK

- Incorporate inductive coupling to substrate: significant in CMOS epi processes
- Improve expressions for the series resistance to include proximity effects
- Extend current sheet approach to handle non-uniform current distributions

CONTRIBUTIONS

- Current sheet approach to inductance calculation
- Simple accurate expression for inductance of sdquare, hexagonal, octagonal and circular spirals
- Expressions for mutual inductance and mutual coupling coefficient
- On-chip transformer models
- Basis for design and synthesis of on-chip inductor and transformer circuits
- Shunt-peaked amplifier with optimized on-chip inductor

• Design

{ Scalable, analytical models for synthesis and optimization

Verification
 { Field solvers